

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	25079127	@ad<"20040115"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/14 14:08
L2	18	l1 and (micro\$1controller microcontroller (micro adj controller) processor microprocessor (micro adj processor) cpu mpu) and (pars\$4 search\$3) and ((lot batch\$4) with wafer) and (test\$4 check\$4 simulat\$4 verif\$5 drc) same ((micro\$1controller microcontroller (micro adj controller) processor microprocessor (micro adj processor) cpu mpu) (wafer)) and voltag\$5 near3 (level operation operating operate limit threshold potential) and (voltag\$5 near3 (level operation operating operate limit threshold potential)) same (defect\$4 fail\$4 fault error)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/14 14:43
L3	13	l1 and (micro\$1controller microcontroller (micro adj controller) processor microprocessor (micro adj processor) cpu mpu) and ((lot batch\$4) with wafer) and (test\$4 check\$4 simulat\$4 verif\$5 drc) with ((micro\$1controller microcontroller (micro adj controller) processor microprocessor (micro adj processor) cpu mpu) (wafer)) and voltag\$5 near3 (level operation operating operate limit threshold potential) and (voltag\$5 near3 (level operation operating operate limit threshold potential)) same (defect\$4 fail\$4 fault error) and ((voltag\$5 near3 (level operation operating operate limit threshold potential)) with (identify\$5 determin\$4 best optimal optimize optimization))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/14 15:00
L4	1	"20040111231" and (processor (micro adj processor) cpu mpu (micro adj controller) microcontroller microprocessor)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/14 15:01

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L5	3	(US-20040128567-\$).did. or (US-6414508-\$ or US-5457695-\$). did.	US-PGPUB; USPAT	OR	ON	2006/03/14 15:36
L6	0	I5 and decompress	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/14 15:36
L7	1	I5 and (decompress zip unzip compress expand)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/14 15:37
L8	0	I5 and (parser)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/14 15:37

	Search Text
1	(test\$4 measur\$4) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$4 level)
2	(test\$4 measur\$4) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$6 level)
3	(test\$4 measur\$4) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$6 level) and test with wafer
4	(test\$4 measur\$4) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$6 level) and test with wafer and @ad<"20040115"
5	(test\$4 measur\$4) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$6 level) and test with wafer and @ad<"20040115" and test\$4 with (defect\$4 bad fail\$5)
6	(test\$4 measur\$4) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$6 level) and test with wafer and @ad<"20040115" and test\$4 with (defect\$4 bad fail\$5) and voltage same (operat\$6 level) same (defect\$4 bad fail\$5)
7	(test\$4 measur\$4) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$6 level) and test with wafer and @ad<"20040115" and test\$4 with (defect\$4 bad fail\$5) and voltage same (operat\$6 level) same (defect\$4 bad fail\$5) and test\$4 same operating\$4 same voltage same (defect\$4 bad fail\$5) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu) wafer)
8	test\$4 same operat\$5 same (different level) same voltage test with wafer and @ad<"20040115" and (test\$4 burn\$5 stress) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$4 different level)
9	test\$4 same operat\$5 same (different multi\$5 level) same voltage and test\$4 with wafer and @ad<"20040115" and (test\$4 burn\$5 stress) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$4 multi\$5 different level) and (test\$4 burn\$5 stress) same (wafer) same voltage same (operat\$4 multi\$5 different level)
10	test\$4 same operat\$5 same (different multi\$5 level) same voltage and test\$4 with wafer and @ad<"20040115" and (test\$4 burn\$5 stress) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$4 multi\$5 different level) and (test\$4 burn\$5 stress) same (wafer) same voltage same (operat\$4 multi\$5 different level) and (test\$4 burn\$5 stress) with (operat\$4 multi\$5 different level) with voltage ^{adj?}
11	test\$4 same operat\$5 same (different multi\$5 level) same voltage and test\$4 with wafer and @ad<"20040115" and (test\$4 burn\$5 stress) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$4 multi\$5 different level) and (test\$4 burn\$5 stress) same (wafer) same voltage same (operat\$4 multi\$5 different level) and (test\$4 burn\$5 stress) with (operat\$4 multi\$5 different level) with voltage

(operat\$5 adj voltage) same for

	Search Text
12	test\$4 same operat\$5 same (different multi\$5 level) same voltage and test\$4 with wafer and @ad<"20040115" and (test\$4 burn\$5 stress) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$4 multi\$5 different level) and (test\$4 burn\$5 stress) same (wafer) same voltage same (operat\$4 multi\$5 different level) and (test\$4 burn\$5 stress) with (operat\$4 multi\$5 different level) with voltage and (operat\$4 multi\$5 different level) with voltage with (fail\$5 bad defect\$4 pass/fail)
13	test\$4 same operat\$5 same (different multi\$5 level) same voltage and test\$4 with wafer and @ad<"20040115" and (test\$4 burn\$5 stress) same (processor microprocessor microcontroller micro adj (processor controller cpu mpu)) same voltage same (operat\$4 multi\$5 different level) and (test\$4 burn\$5 stress) same (wafer) same voltage same (operat\$4 multi\$5 different level) and (test\$4 burn\$5 stress) with (operat\$4 multi\$5 different level) with voltage and (operat\$4 multi\$5 different level) with voltage with (fail\$5 bad defect\$4 pass/fail) and (select\$5 identif\$5 determin\$5) with (best optim\$6) with voltage